

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination ABE ET AL.	
			Examiner Max Shikhman	Art Unit 2609	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0033674 A1	10-2001	Chen et al.	382/100
*	B	US-2002/0009208 A1	01-2002	Alattar et al.	382/100
*	C	US-2002/0031240 A1	03-2002	Levy et al.	382/100
*	D	US-2002/0059520 A1	05-2002	Murakami et al.	713/176
*	E	US-2002/0051560 A1	05-2002	Donescu et al.	382/100
*	F	US-2002/0083324 A1	06-2002	Hirai, Jun	713/176
*	G	US-6,449,380 B1	09-2002	Acharya et al.	382/100
*	H	US-2002/0157005 A1	10-2002	Brunk et al.	713/176
*	I	US-2003/0161496 A1	08-2003	HAYASHI et al.	382/100
*	J	US-2004/0047489 A1	03-2004	Seo et al.	382/100
*	K	US-6,990,213 B2	01-2006	Donescu, Ioana	382/100
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
*	U	Jue Wang, May 2001, IEEE, Consumer Electronics IEEE Transactions on, Volume: 47 Issue: 2, 257-262		
	V			
	W			
	X			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.